## COE 360, Term 071

## Principles of VLSI Design Quiz# 1

## Date: Wednesday, Sep. 29, 2004

## **Q1.** Fill in the blank:

(1)	is the motion of charges due to the application of an
	electric field.
(2)	is the motion of charges resulting from a non-uniform charge distribution.
	C
(3)	The current per unit area in a conducting medium is called the
(4)	describes the ease with which charge carriers drift in the
	material.
(5)	Drift velocity with the increase of the area of a conducting medium.
(6)	Drift velocity with the increase of the charge carriers concentration per unit volume.
(7)	The conductivity of a material increases with the increase in the and
(8)	The electric field across a conductor increases with the increase in
(9)	The resistance of a conductor increases with the increase in and the decrease in and and
(10)	A silicon atom has electrons, of which are valence electrons.
(11)	At T=0°K, all the valence electrons in a silicon semiconductor are in the band.
(12)	semiconductors are pure crystals that contain no foreign
	atoms or impurities
(13)	energy is the energy level below which all the energy states are filled with electrons and above which all the states are empty at $T=0^{\circ}K$ .
(14)	In an intrinsic semiconductor, at a given temperature, the concentration of free electrons isthe concentration of free holes.

- (15) The addition of trivalent atoms to an intrinsic semiconductor results in a \_\_\_\_\_type material, while the addition of pentavalent atoms to an intrinsic semiconductor results in a \_\_\_\_\_type.
- (16) The majority charge carriers in an n-type material are \_\_\_\_\_\_ while the minority charge carriers are \_\_\_\_\_\_.
- (17) The mass action law states that under thermal equilibrium, the concentration of free electrons times the concentration of free holes is constant and is equal to
- (18) If an intrinsic semiconductor material is doped with acceptor impurities, the number of free holes \_\_\_\_\_\_ while the number of free electrons

.

- (19) The charge neutrality law states that under thermal equilibrium, the semiconductor crystal is electrically \_\_\_\_\_\_.
- (20) The concentration of free electrons in an n-type material doped with donor concentration N<sub>d</sub> is nearly \_\_\_\_\_\_ and the concentration of free holes is \_\_\_\_\_\_.
- (21) The conductivity of a semiconductor material \_\_\_\_\_ with increasing temperature.
- (22) The Fermi level for an n-type semiconductor is \_\_\_\_\_\_ the intrinsic Fermi level  $E_{Fi}$  while the Fermi level for a p-type semiconductor is \_\_\_\_\_\_  $E_{Fi}$ .
- (23) As the doping level increases, the Fermi energy level moves closer to the valence band for the \_\_\_\_\_ material and closer to the conduction band for the \_\_\_\_\_ material.
- (25) Increasing the doping concentration \_\_\_\_\_\_ the built-in potential across the PN junction.
- (26) The width of the depletion region \_\_\_\_\_ with increasing the doping concentration.
- (27) In a reverse biased PN junction, the junction potential \_\_\_\_\_\_ and the depletion region width \_\_\_\_\_.
- (28) If a positive voltage is applied to the p-region with respect to the n-region, the PN junction is called \_\_\_\_\_\_.
- (29) Transition capacitance across the PN junction \_\_\_\_\_ with increasing the doping concentration.
- (30) The higher the doping concentrations of the PN junction are the \_\_\_\_\_\_ the breakdown voltage.

**Q2.** Determine the <u>electron and hole concentrations</u> and the <u>conductivity</u> of a piece of silicon at 300°K given that it is doped with Arsenic (pentavalent) at a density of  $4X10^{16}$  atoms/cm<sup>3</sup> and doped with Boron (trivalent) at a density of  $4X10^{12}$  atoms/cm<sup>3</sup>. Assume the following: Electron mobility at 300°K=1500 cm<sup>2</sup>/V.s, Hole mobility at 300°K = 475 cm<sup>2</sup>/V.s, Intrinsic concentration at 300°K=1.45X10<sup>10</sup> cm<sup>-3</sup>, q= 1.6X10<sup>-19</sup>. Indicate clearly the <u>units</u> in your solution.